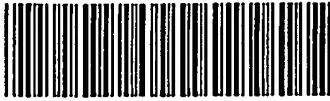


# Search Notes



Application/Control No.

10/824,480

Examiner

Sang Y. Paik

Applicant(s)/Patent under  
Reexamination

SUNG ET AL.

Art Unit

3742

## SEARCHED

Class	Subclass	Date	Examiner
219	443.1 450.1		
	451.1		
	452.11		
	452.12		
99	422 425 444 445 447		
		3/13/06	JP
up to 2		9/1/06	

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST TEST SEARCHED	3/13/06	JP